International Application No.: PCT/JP2004/015213

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September 19, 2005

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REMARKS

Claims 10-35 are pending in this application. By this Preliminary Amendment, Applicants AMEND the specification and the abstract of the disclosure, CANCEL claims

1-9 and ADD new claims 10-35.

Applicants have attached hereto a Substitute Specification in order to make

corrections of minor informalities contained in the originally filed specification.

Applicants' undersigned representative hereby declares and states that the Substitute

Specification filed concurrently herewith does not add any new matter whatsoever to the

above-identified patent application. Accordingly, entry and consideration of the

Substitute Specification are respectfully requested.

The changes to the specification have been made to correct minor informalities

to facilitate examination of the present application.

Applicants respectfully submit that this application is in condition for allowance.

Favorable consideration and prompt allowance are respectfully solicited.

Respectfully submitted,

Date: September 19, 2005

Attorneys for Applicants

Joseph R. Keating

Registration No. 37,368

Christopher A. Bennett

Registration No. 46,710

**KEATING & BENNETT, LLP** 

8180 Greensboro Drive, Suite 850 Tyson's Corner, Virginia 22102 Telephone: (703) 637-1480

Facsimile: (703) 637-1499

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# MARKED-UP VERSION OF ENGLISH TRANSLATION OF INTERNATIONAL APPLICATION AS ORIGINALLY FILED

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#### DESCRIPTION

Attorney Docket No. 36856.1370

#### CERAMIC MULTILAYER SUBSTRATE

#### TECHNICAL BACKGROUND OF THE INVENTION

# 1. Field of the Invention

The present invention relates to a ceramic multilayer substrate.

# Background2. Description of the Related Art

Various high-frequency modules, e.g., chip antennas, delay lines, high-frequency combination switch modules, and receiving devices, are mounted in the inside of information communications apparatuses, e.g., portable terminals. Such a high-frequency module is used-in-the condition of being mounted on a wiring substrate.

In general, circuit components are mounted on a multilayer substrate in such a high-frequency module.

Multilayer substrates composed of including ceramic multilayer substrates are well-known. Most of ceramic multilayer substrates are provided with ground electrodes in order to eliminate noise. This is disclosed in Japanese

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Unexamined Patent Application Publication No. 2002-94410 (Patent Document 1), for example.

In general, ground electrodes are built provided in the inside of ceramic multilayer substrates at positions locations as close to the bottom surfaces as possible. This is because unnecessary impedance components, e.g., stray capacitances and stray inductances, are readily eliminated by bringingarranging the ground electrodes as close to ground electrodes of wiring substrates as possible.

Fig. 8 shows an example of <u>a</u> known ceramic multilayer substrates. In a ceramic multilayer substrate 100, electronic components 13a, 13b, and 13c are mounted on a ceramic laminate 10 <u>composed of including laminated</u> ceramic layers 11—<u>laminated</u>. A ground electrode 12 is <u>built</u> <u>provided</u> in the vicinity of a bottom surface of the ceramic multilayer substrate 100 <u>while being</u> and is sandwiched between ceramic layers 11m and 11n.

Patent-Document-1: Japanese-Unexamined Patent Application
Publication No. 2002 94410

#### Disclosure of Invention

# Problems to be Solved by the Invention

The ground electrode requires a wide area and, therefore, a conductor pattern having a wide area must be formedprovided on a ceramic green sheet in the during

production of a ceramic multilayer substrate. However, as the area of the conductor pattern is increased, the mutual contact area of the two ceramic green sheets sandwiching the conductor pattern therebetween is decreased. decreases. As a result, the bondability between the ceramic green sheets is reduced.

As for the example, In the ceramic multilayer substrate 100, shown in Fig. 8, the bondability between the ceramic green sheets 11m and 11n is reduced due to an increase in the area of the ground electrode 12 sandwiched by the ceramic green sheets 11m and 11n.

Furthermore, the ceramic layers are loaded due to the difference in the amount of shrinkage between the conductor pattern and the ceramic green sheets occurred during baking. This The effect of this load exerts a larger effect increases as the area of the conductor pattern is increased. Consequently, there is a problem in that inconveniences, e.g., delamination and crack, ofs in the ceramic layers are present often occur, particularly in the vicinity of the ground electrode of the ceramic multilayer substrate after baking.

In order to overcome this problem, there is an idea that the ground electrode is disposed while being has been provided so as to be exposed aton the bottom surface of the ceramic multilayer substrate. This structure has been in

practical use. However, in that case, another problem occurs in that a short circuit tends to occur often occurs between the ground electrode and wirings on the wiring substrate.

--- Accordingly, it is an object

# SUMMARY OF THE INVENTION

embodiments of the present invention to provide a ceramic multilayer substrate, wherein having a ground electrode is disposed at a ground electrode can be disposed at a position in extremely close proximity to a wiring substrate without occurrence of causing a short circuit between the ground electrode and the wiring substrate even when the ceramic multilayer substrate is mounted on the surface of the wiring substrate and, in addition, inconveniences problems, e.g., cracks, do not occur during the baking.

# Means for Solving the Problems

\_\_\_\_\_\_In order to achieve the above described object, a\_\_\_A ceramic multilayer substrate according to a first aspectpreferred embodiment of the present invention is provided withincludes a ceramic laminate including a plurality of laminated ceramic layers—laminated, having a first main surface, and including internal circuit elements

disposed in the inside; thereof, a resin layer having a bonding surface in contact with the first main surface of the above-described ceramic laminate and a mounting surface opposite to the  $\frac{above-described}{bonding}$  surface<sub> $\frac{1}{L}$ </sub> external electrodes, each disposed on the mounting surface of the above described resin layer and electrically connected to at least one of the internal circuit elements of the abovedescribed ceramic laminate; and a ground electrode, a dummy electrode, or capacitor-forming electrodes disposed at an interface between the first main surface of the abovedescribed ceramic laminate and the bonding surface of the above-described resin layer or in the inside of the abovedescribed resin layer. By adopting With this configuration, the ground electrode, the dummy electrode, or the capacitorforming electrodes can be held at the positionare disposed at a location in extremely close proximity to the mounting surface. As a result, the distance between the ground electrode, the dummy electrode, or the capacitor-forming electrodes and the wiring substrate can be is greatly decreased.

<u>The above aspect</u>, <u>Preferably</u>, the ground electrode, the dummy electrode, or the capacitor electrodes are preferably, the above described ground electrode, the dummy electrode, or the capacitor forming electrodes are made of a sintered metal integrally baked with the above described

ceramic laminate. By adopting With this configuration, the surface roughness of the electrode itself is increased as compared with to that in the case where the of an electrode that is formed by attaching metal foil, and the bonding forth can be strength is increased by virtue of due to an anchor effect with respect to of bonding to the resin layer.

In-order to achieve the above-described object, a A ceramic multilayer substrate according to a second aspectpreferred embodiment of the present invention is provided with includes a ceramic laminate including a plurality of laminated ceramic layers laminated, having a first main surface, and including internal circuit elements disposed in the inside; thereof, a resin layer having a bonding surface in contact with the first main surface of the above-described-ceramic laminate and a mounting surface opposite to the above-described bonding surface, external electrodes, each disposed on the mounting surface of the above described resin layer and electrically connected to at least one of the internal circuit elements of the abovedescribed ceramic laminate, a ground electrode disposed at an interface between the first main surface of the abovedescribed ceramic laminate and the bonding surface of the above-deseribed-resin layer or in the inside of the abovedescribed resin layer, and capacitor forming electrodes facing the above described ground electrode from the side

opposite to the above described mounting surface so such that capacitors are constructed defined by the above described ground electrode and the capacitor—forming electrodes. By adopting with this configuration, capacitors having very stable characteristics can be produced are provided.

--- In the above-described aspect, preferably,

Preferably, first circuit components mounted on the above described—first main surface and covered with the above described—resin layer are provided, wherein the above—described—ground electrode, the dummy electrode, or the capacitor—forming electrodes are disposed on the side nearer\_closer to the above—described—mounting surface than are—the above—described—first circuit components. By adoptingWith this configuration, the electronic components can be—are—mounted not only on the top surface of the ceramic laminate, but also on the bottom surface.

Consequently, an increase in the density of electronic components and space saving of wiring substrates can be—are achieved.

InPreferably, the above described aspect, preferably, the above described first circuit components are disposed within the region determined by projecting the above described ground electrode, the dummy electrode, or the capacitor—forming electrodes on the above described—first

main surface. By adopting With this configuration, the ground electrode can exert provides a shielding effect on the first circuit components.

In the above described aspect, preferably Preferably, the electrical connections from the above described external electrodes to the above described internal circuit elements are performed through provided by relay electrodes disposed arranged so as to extend along the above described first main surface. By adoptingWith this configuration, the position location of an upper via and the position location of a lower via can be shifted from with respect to each other. Therefore, the flexibility in the design can be is increased.

ImPreferably, the above-described aspect, preferably, the above described—ceramic laminate has a second main surface on the side—opposite side—to the above-described first main surface, and second circuit components are mounted on the above-described—second main surface. By adoptingWith this configuration, an increase in the density of electronic components and space saving of wiring substrates ean—be—is achieved.

In the above-described aspect, preferably Preferably, a conductor case is disposed on the above-described second main surface to cover the above-described second circuit components. By-adoptingWith this configuration, since the second circuit components are covered with the conductor

case, the second circuit components are shielded against external electromagnetic waves, and leakage of electromagnetic waves generated <a href="fromby">fromby</a> the second circuit components to the outside <a href="ean-is">ean-is</a> also <a href="be-prevented">be-prevented</a>.

In Preferably, the above-described aspect, preferably, the above-described second circuit components on the above-described second main surface are covered with a molded resin layer (25). By adopting. With this configuration, the second circuit components are protected from, for example, collision with other components.

# **Advantages**

According to preferred embodiments of the present invention, the ground electrode ean be held arranged at thea position in extremely close proximity to the mounting surface. As a result, the distance between the ground electrode and the wiring substrate ean be decreased. Since the necessity for any a ceramic layer under the ground electrode ean be is avoided, it is possible to prevent the problem that delamination or erack occur in the ceramic layers under the ground electrode during baking. Furthermore, since the ground electrode is covered with the resin layer, occurrence of short eircuit circuiting between the ground electrode and the electrode of the wiring substrate ean be is prevented even when this ceramic

multilayer substrate is mounted on the surface of the wiring substrate.

# Brief Description of the Drawings

Other features, elements, steps, advantages and characteristics of the present invention will become more apparent from the following detailed description of preferred embodiments thereof with reference to the attached drawings.

# BRIEF DESCRIPTION OF THE DRAWINGS

Fig. 1 is a sectional view of a ceramic
multilayer substrate in according to a first preferred
embodiment according toof the present invention.
[Fig. 2] Fig. 2 is a sectional view of a ceramic
multilayer substrate in according to a second preferred
embodiment according toof the present invention.
[Fig. 3] — Fig. 3 is a sectional view of a ceramic
multilayer substrate in according to a third preferred
embodiment according toof the present invention.
[Fig. 4]Fig. 4 is a sectional view of a ceramic
multilayer substrate in according to a fourth preferred
embodiment according toof the present invention.
<del>[Fig. 5]</del> Fig. 5 is a sectional view of a ceramic
multilayer substrate inaccording to a fifth preferred

embodiment according toof the present invention.

[Fig. 6] \_\_\_\_\_ Fig. 6 is a sectional view of another example of the ceramic multilayer substrate in the fifth preferred embodiment according toof the present invention.

[Fig. 7] \_\_\_\_ Fig. 7 is a sectional view of a ceramic multilayer substrate inaccording to a sixth preferred embodiment according toof the present invention.

[Fig. 8] \_\_\_\_ Fig. 8 is a sectional view of a ceramic multilayer substrate according to a known technology.

# Reference Numerals DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS

electrode, 13a, 13b, and 13e electronic component, 14 internal circuit element, 15 resin layer, 16 mounting surface, 17 external electrode, 18 first main surface, 19 bonding surface, 20 capacitor forming electrode, 21 relay electrode, 22a, 22b, and 22e electronic component, 23 second main surface, 24 conductor case, 25 molded resin layer, 100, 101, 102, 103, Herein, the terms "upper" and 104 ceramic multilayer substrate.

# Best Mode-for Carrying-Out the Invention

Hereafter, the concept of upper or \_\_\_lower\_\_ do not refer to absolutely upper or lower\_the absolute top or bottom, but

rather, refer to upper orand lower portions relative to apparent positions locations shown in the reference drawing.

(First embodiment)

# First Preferred Embodiment

A ceramic multilayer substrate 101 in theaccording to a first preferred embodiment according to of the present invention will be described with reference to Fig. 1. This ceramic multilayer substrate 101 is provided with a ceramic laminate 10 composed of including a plurality of laminated ceramic layers 11-laminated. Internal circuit elements 14 are disposed in the inside of the ceramic laminate 10. internal circuit elements 14 includes include via hole conductors penetrating extending in ceramic layers 11 in a direction of lamination and in-plane conductors disposed at interfaces between the ceramic layers 11. The ceramic laminate 10 hasincludes a bottom surface serving as defining a first main surface 18. A ground electrode 12 is disposed arranged so as to cover the first main surface 18 of the ceramic laminate 10. Furthermore, a resin layer 15 is disposed-arranged so as to cover the ground electrode 12.

The resin layer 15 has includes a bonding surface 19 in contact with the first main surface 18 and a mounting surface 16 opposite to the bonding surface 19. External electrodes 17 are disposed on the mounting surface 16. That

is, in the present <u>preferred</u> embodiment, the ground electrode 12 is disposed at the interface between the first main surface 18 of the ceramic laminate 10 and the bonding surface 19 of the resin layer 15.

The external electrode 17 is electrically connected to at least one of the internal circuit elements 14 through a via hole disposed in the resin layer 15. Some external electrodes 17 do not seemappear to be connected to any internal circuit element 14 in the drawing. Fig. 1. However, these are connected to respective internal circuit elements 14 at positions locations not shown in this sectional view. The ceramic laminate 10 has includes a top surface serving as defining a second main surface 23 opposite to the first main surface 18. Electronic components 13a, 13b, and 13c are mounted on the second main surface 23.

The ceramic layer 11 can be formed from a ceramic material that is capable of being sintered at a low temperature. The ceramic material capable of being sintered at a low temperature refers to a ceramic material which can be baked at a temperature of about 1,000°C or less.

Examples thereof ean—include glass composite materials produced by mixing a ceramic powder, e.g., alumina, forsterite, or cordierite, with borosilicate glass—or the like, crystallized glass materials composed of including ZnO-MgO-Al<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> base crystallized glass, and non-glass

materials composed of including, e.g., BaO-Al<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> base ceramic powders and Al<sub>2</sub>O<sub>3</sub>-CaO-SiO<sub>2</sub>-MgO-B<sub>2</sub>O<sub>3</sub> base ceramic powders. The ceramic layers 11 are composed of include ceramic material that is capable of being sintered at a low temperature and, thereby, low resistance and low melting point metallic materials, e.g., Ag or Cu, can be used as a metallic material constituting defining the internal circuit elements 14 in the ceramic laminate 10. Consequently, the ceramic laminate 10 and the internal circuit elements 14 disposed therein can be produced by simultaneous baking at about 1,000°C or less.

Preferably, the ground electrode 12 disposed between the first main surface 18 of the ceramic laminate 10 and the bonding surface 19 of the resin layer 15 is formed to constitute withhas an area that is in the range of about 3% to about 98% of the area of the first main surface 18, and more preferably of the range of about 40% to about 95%. This is because the bonding forthstrength of the resin layer described below is greatly increased. The thickness of the resin layer 15 is about 5 µm to about 500 µm, and preferably is about 10 toµm to about 300 µm. The thickness may be smallerless than the thickness of the ceramic laminate 10. This is because the connection distance from the ground electrode of the mother substrate is decreased and, thereby, the value of parasitic inductance can be decreased, so

such that excellent high-frequency characteristics can be
exertedare provided, particularly in applications at high
frequencies.

The ground electrode 12 may be an electrode made of metal foil, e.g., copper foil, but. However, preferably is anthe ground electrode 12 is made of a sintered metal. general, the surface of the ceramic laminate 10 has a surface roughness Rmax at the same level as that of common copper foil. That is, the Rmax is a few micrometers and, therefore, the bonding forthstrength to the resin layer 15 is weak.relatively low. Since the surface roughness Rmax of the sintered metal is a—several tens of micrometers, and is an order of magnitude largergreater than the surface roughness Rmax of the copper foil-of a few micrometers, when the ground electrode 12 made of the sintered metal is interposed between the ceramic laminate 10 and the resin layer 15, the bonding strength between the ground electrode 12 and the resin layer 15 can be is increased by the anchor effect of the sintered metal. The above-described difference in the surface roughness results from that the copper foil is-being formed by plating or rolling of a copper plate, whereas the sintered metal is formed by baking a conductive paste containing about 10 toto about 40 percent by volume of resin, referred to as varnish, the resin component is burnt off to leave voids in the inside or on

the surface and, thereby, the surface roughness is increased.

The ground electrode 12 is an electrode which is at a ground potential—(earth potential). Other electrodes may be disposed in place of the ground electrode 12. In that case, it is essential only that the electrode taking the place of the ground electrode 12 is an electrode having a large area as described above. For example, the electrode may be a dummy electrode that is electrically independent of the internal circuit elements 14, or be—a capacitor—forming electrode to formwhich defines a capacitor in combination with any other electrode.

The ceramic multilayer substrate 101 in the present preferred embodiment can be is preferably produced as described below.

A conductive paste is patterned on a ceramic green sheet and, thereby, a predetermined conductor pattern to become define internal circuit elements 14 is formed on the ceramic green sheet. Likewise, a plurality of ceramic green sheets having predetermined conductor patterns are produced. The plurality of ceramic green sheets are laminated while sandwiching the conductor patterns therebetween. A conductor pattern to become define the ground electrode 12 is formed on the back of the thus produced unbaked laminate to become the ceramic laminate 10. Alternatively, a conductor pattern to become define the ground electrode 12 is formed on

a ceramic green sheet, the resulting ceramic green sheet is laminated and, thereby, an unbaked laminate having the conductor pattern to becomedefine the ground electrode 12 ean beis produced.

The thus produced resulting structure is then baked. As a result, the unbaked laminate is converted to the ceramic laminate 10 which is made of a sintered ceramic, and the conductor pattern to become define the ground electrode is converted to the ground electrode 12 made of a sintered metal.

Furthermore, a resin sheet in a semi-hardened state, that is, in a state of B stage, is laminated so as to cover the ground electrode 12, followed by curing, sesuch that the resin layer 15 is produced. Through holes are bored formed in the resin layer 15 with a laser or the likeother suitable device, and are filled in with an electrically conductive material, e.g., an electrically conductive resin or solder. Alternatively, a resin sheet having through holes filled in with an electrically conductive material in advance may be laminated. Subsequently, electrodes are formed from metal foil or the likeother suitable material on the surface of the resin layer 15, se such that the external electrodes 17 are produced. With respect to the external electrodes 17, end surfaces of the conductive materials disposed in the resin layer may be used as external electrodes. On the

other hand, surface-mount electronic components 13a, 13b, and 13c, e.g., semiconductor devices and chip type monolithic capacitors, are mounted on the top surface of the ceramic laminate 10. In this manner, the ceramic multilayer substrate 101 shown in Fig. 1 ean beis produced.

In the present preferred embodiment, the ground electrode 12 can be heldarranged at a position location in extremely close proximity to the mounting surface 16. That the The ground electrode 12 is close to the mounting surface 16 refers to that the ground-electrode 12 becomes thus arranged extremely close to the wiring substrate (not shown in the drawing), e.g., a mother board, during mounting. the present preferred embodiment, since no ceramic layer is disposed under the ground electrode 12, it is possible to prevent the problem that the problems of delamination or erack occurs and cracks occurring in ceramic layers under the ground electrode during baking are prevented. Furthermore, since the ground electrode 12 is covered with the resin layer 15, occurrence of short circuitcircuiting between the ground electrode 12 and the electrode of the wiring substrate can be is prevented even when the ceramic multilayer substrate 101 is mounted on the surface of the wiring substrate (not shown in the drawing).

Preferably, the ground electrode 12 is made of a sintered metal that is integrally baked with the ceramic

laminate 10. This is because when the electrode is integrally baked, the bonding forthstrength between the ceramic laminate 10 and the ground electrode 12 is increased and, in addition, since the surface roughness of the electrode itself is increased as compared withto that in the case wherein which the electrode is formed by attaching metal foil, e.g., copper foil, the bonding forth can bestrength is increased by virtue of due to an anchor effect with respect to bonding to the resin layer 15, as described above.

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# Second embodiment) Preferred Embodiment

A ceramic multilayer substrate 102 in the according to a second preferred embodiment according to of the present invention will be described with reference to Fig. 2. In this ceramic multilayer substrate 102, the ground electrode 12 is disposed while avoiding contact with the first main surface 18. That is, the ground electrode 12 is disposed in the inside of the resin layer 15, and is disposed while being sandwiched by the resin layer 15 from above and below, so as to prevent contact with the first main surface 18. The configurations of the other portions are similar to those described in the first preferred embodiment.

In the present <u>preferred</u> embodiment, there is no portion in which the ground electrode 12 and the ceramic

layer 11 are in direct contact with each other, and therefore, problems, e.g., <a href="mailto:eracks">erackcracks</a> resulting from the difference in heat shrinkage <a href="mailto:between">behavior</a>—between the ground electrode 12 and the ceramic layer 11 <a href="mailto:can be further are">can be further are</a> reliably <a href="mailto:avoided">avoided</a> prevented.

The structure shown in Fig. 2 canmay be constructed by laminating a plurality of resin sheets over a plurality of times—to form the resin layer 15, and inserting copper foil between the sheets. The copper foil interposed in the inside of the resin layer 15 serves as defines the ground electrode 12.

(Third-embodiment)

# Third Preferred Embodiment

A ceramic multilayer substrate 103 in theaccording to a third preferred embodiment according to of the present invention will be described with reference to Fig. 3. In this ceramic multilayer substrate 103, the capacitor—forming electrodes 20 are disposed provided in addition to the ground electrode 12 on the surface of an internal layer of the resin layer 15. The capacitor—forming electrodes 20 are electrodes which face the ground electrode 12 from the side opposite to the mounting surface 16 and, thereby, constructdefine capacitors in combination with the ground electrode 12. These capacitors are electrically connected

to the internal circuit elements 14 to <u>constitutedefine</u>
predetermined circuits. The configurations of the other
portions are similar to those described in the second

<u>preferred embodiment</u>. The capacitor—<u>forming</u> electrodes 20
may be <u>disposedprovided</u> at the interface between the ceramic laminate 10 and the resin layer 15.

In this ceramic multilayer substrate 103, the capacitors are <u>formeddefined</u> by the capacitor—<u>forming</u> electrodes 20 and the ground electrode 12. In this manner, capacitors having very stable characteristics <u>ean-beare</u> produced.

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# Fourth embodiment) Preferred Embodiment

A ceramic multilayer substrate 104 in the according to a fourth preferred embodiment according to of the present invention will be described with reference to Fig. 4. In this ceramic multilayer substrate 104, surface-mount electronic components 22a, 22b, and 22c, such as semiconductor devices and chip type monolithic capacitors, are surface-mounted as first circuit components on the first main surface 18 which is the bottom surface of the ceramic laminate 10. The resin layer 15 is formedarranged to cover the electronic components 22a, 22b, and 22c. The ground electrode 12 is disposed on the side nearercloser to the mounting surface 16 than are—the electronic components 22a,

22b, and 22c, that is, below the electronic components. The configurations of the other portions are similar to those described in the secondsecond preferred embodiment.

In the present <u>preferred</u> embodiment, the electronic components <u>can</u> <u>be</u> <u>are</u> mounted not only on the top surface of the ceramic laminate 10, but also on the bottom surface.

Consequently, an increase in the density of electronic components and space saving of wiring substrates <u>can</u> <u>be</u> <u>are</u> achieved.

In particular, as shown in Fig. 4, preferably, the electronic components 22a, 22b, and 22c serving—asdefining the first circuit components are disposed within the region determined by projecting the ground electrode 12 on the first main surface 18. This is because the ground electrode 12 exertsprovides a shielding effect on the first circuit components by adopting—such a in this configuration.

As shown in Fig. 3 and Fig. 4, the ceramic multilayer substrates 103 and 104 are provided with relay electrodes 21 disposed—arranged so as to extend along the first main surfaces 18. The electrical connection from the external electrode 17 to the internal circuit element 14 is performed throughprovided via the relay electrode 21. There is an idea that the electrical connection from the external electrode 17 to the internal circuit element 14 is performed and electrode 17 to the internal circuit element 14 is performed by direct via-to-via connection.

However, it is preferable to interpose provide the relay electrode 21, as shown in Fig. 3 and Fig. 4, since because the position location of an upper via and the position of a lower via can be shifted from with respect to each other and, therefore, Therefore, the flexibility in the design can be is increased. This is not limited to the ceramic multilayer substrates 103 and 104 in the third and fourth preferred embodiments. The same holds true in the other preferred embodiments.

As is—shown in each of the above-described preferred embodiments, preferably, the second main surface 23 is disposed on the side opposite to the first main surface 18, and surface-mount electronic components 13a, 13b, and 13c, such as semiconductor devices and chip type monolithic capacitors, are mounted as second circuit components on the second main surface 23. This is because a multifunctional high-frequency module can be constructed by adoptingusing such a configuration.

(Fifth embodiment)

#### Fifth Preferred Embodiment

A ceramic multilayer substrate 105 in the fifth

preferred embodiment according to the present invention will
be described with reference to Fig. 5. This ceramic

multilayer substrate 105 corresponds to the ceramic

multilayer substrate 101 in the first <u>preferred</u> embodiment, in which a conductor case 24 is attached <u>so as</u> to cover the electronic components 13a, 13b, and 13c <u>serving as defining</u> the second circuit components mounted on the second main surface 23.

In the present <u>preferred</u> embodiment, since the second circuit components are covered with the conductor case 24, the second circuit components are shielded against external electromagnetic waves, and leakage of electromagnetic waves generated <u>from</u> by the second circuit components to the outside <u>canis</u> also <u>be</u> prevented. Therefore, this is <u>preferable</u>.

The present <u>preferred</u> embodiment was described with reference to the <u>example based on the</u> ceramic multilayer substrate 101 in the first <u>preferred</u> embodiment. However, as shown in Fig. 6, the conductor case 24 may be attached to the ceramic multilayer substrate <u>106</u>, which is similar to the ceramic multilayer substrate 104 in the fourth <u>preferred</u> embodiment. Alternatively, the conductor case 24 may be attached to the ceramic multilayer substrate in the second <u>preferred</u> embodiment or the third <u>preferred</u> embodiment.

(Sixth embodiment)

# Sixth Preferred Embodiment

A ceramic multilayer substrate 107 in the sixth

preferred embodiment according to the present invention will be described with reference to Fig. 7. This ceramic multilayer substrate 107 corresponds to the ceramic multilayer substrate 101 in the first preferred embodiment, in which a molded resin layer 25 is disposed provided to cover the electronic components 13a, 13b, and 13c serving as defining the second circuit components mounted on the second main surface 23. Therefore, the detailed configurations of the other portions are similar to those described in the first preferred embodiment.

In the present <u>preferred</u> embodiment, since the second circuit components are covered with the conductor case 24, the second circuit components are protected from, for example, collision with other components. The present <u>preferred</u> embodiment was described with reference to the <u>example based on the ceramic multilayer substrate 101 in the first <u>preferred</u> embodiment. In addition to this <u>However</u>, the conductor case 24 may be attached to any one of the ceramic multilayer substrates <u>inaccording to</u> the second, third, and fourth preferred embodiments.</u>

Every embodiment disclosed in the above described present specification is no more than an exemplification.

The scope of the present invention is not limited to the above description, but is indicated by the claims. The present invention includes any spirit and scope equivalent

to those of the claims and all modifications within the scope of the claims.

# Industrial Applicability

The present invention can be applied to ceramic multilayer substrates generally used for high-frequency modules mounted in the inside of information communications apparatuses, for example.

While the present invention has been described with respect to preferred embodiments, it will be apparent to those skilled in the art that the disclosed invention may be modified in numerous ways and may assume many embodiments other than those specifically set out and described above.

Accordingly, it is intended by the appended claims to cover all modifications of the present invention which fall within the true spirit and scope of the invention.